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| Notice of References Cited | | Application/Control No. 10/530,436 | Applicant(s)/Patent Under Reexamination SHEN ET AL. | |
| | | Examiner HEE SOO KIM | Art Unit 2157 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,012,098 A | 01-2000 | Bayeh et al. | 709/246 |
| * | B | US-2001/0049733 A1 | 12-2001 | Tokumaru et al. | 709/225 |
| * | C | US-6,345,298 B1 | 02-2002 | Moriya, Koji | 709/228 |
| * | D | US-2002/0138495 A1 | 09-2002 | Chang et al. | 707/102 |
| * | E | US-2002/0143972 A1 | 10-2002 | Christopoulos et al. | 709/231 |
| * | F | US-2003/0079057 A1 | 04-2003 | Ruskin et al. | 710/1 |
| * | G | US-6,556,217 B1 | 04-2003 | Makipaa et al. | 345/667 |
| * | H | US-2003/0110234 A1 | 06-2003 | Egli et al. | 709/217 |
| * | I | US-2003/0156108 A1 | 08-2003 | Vetro, Anthony | 345/418 |
| * | J | US-2004/0107109 A1 | 06-2004 | Nakanishi et al. | 705/001 |
| * | K | US-7,016,963 B1 | 03-2006 | Judd et al. | 709/228 |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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